



image

2829

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE  
(Case No. 219.003-US)

the Application of: **Yamada**

Serial No: **09/865,528**

Filed: **May 29, 2001**

Title: **Semiconductor Device Test Method and  
Semiconductor Device Tester**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

)  
) Group  
) Art Unit: **2829**  
)  
) Before  
) Examiner: **V. Nguyen**

I hereby certify that this correspondence  
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Patents, P.O. Box 1450, Alexandria, VA  
22313-1450 on March 15, 2004

Michiko Sites  
Date  
(person signing this certificate)

Michiko Sites  
Signature

**INFORMATION DISCLOSURE STATEMENT**

Dear Sir:

Submitted herewith are two (2) sheets of a modified Form PTO-1449. A copy of  
each document cited on the attached Form PTO-1449 is also submitted.

Notably, the documents listed on the attached Form PTO-1449 were identified  
and/or cited in applications (namely, U.S. App. Serial Nos. 09/451,440 and 09/702,831)  
that include subject matter which is similar to that in the above-reference application.

It is respectfully requested that the Examiner make his/her consideration of these  
documents formally of record with the initial Office Action.

Respectfully submitted,

Date: March 15, 2004

Neil A. Steinberg, Reg. No. 34,735  
650-968-8079



PTO-1449 (Modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT	ATTY. DOCKET NO.	SERIAL NUMBER
	219.003-US	09/865,528
	APPLICANT(S) Yamada	
	FILING DATE	GROUP ART UNIT
	May 29, 2001	2829

## U.S. PATENT DOCUMENTS

EXAMINER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE
	4,988,877	1/1991	Stokowksi et al.			
	4,949,162	8/1990	Tamaki et al.			
	5,001,536	3/1991	Fukuzawa et al.			
	5,327,012	7/1994	Yano et al.			
	5,412,210	5/1995	Todokoro et al.			
	5,637,186	6/1997	Liu et al.			
	5,780,870	7/1998	Maeda et al.			

## FOREIGN PATENT DOCUMENTS

EXAMINER INITIALS	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	TRANSLATION YES/NO
	6-273297	9/1994	Japan			
	7-66172	3/1995	Japan			
	57-6310	1/1996	Japan			
	8-313244	11/1996	Japan			
	9-61142	3/1997	Japan			
	10-300450	11/1998	Japan			
	50-63990	5/1975	Japan			
	62-19707	1/1987	Japan			
	8-5528	1/1996	Japan			

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)


EXAMINER	DATE CONSIDERED
EXAMINER: Initial citation if reference was considered. Draw line through citation if not in conformance to MPEP 609 and not considered. Include copy of this form with next communication to applicant.	



PTO-1449 (Modified)  U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE  INFORMATION DISCLOSURE STATEMENT BY APPLICANT	ATTY. DOCKET NO. <b>219.003-US</b>	SERIAL NUMBER <b>09/865,528</b>
	APPLICANT(S) <b>Yamada</b>	
	FILING DATE <b>May 29, 2001</b>	GROUP ART UNIT <b>2829</b>

## U.S. PATENT DOCUMENTS

EXAMINER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE
	5,900,645	5/1999	Yamada			
	6,037,588	3/2000	Liu et al.			
	6,127,193	10/2000	Bang et al.			
	6,317,514	11/2001	Reinhorn et al.			
	5,280,176	1/1994	Jach et al.			

## FOREIGN PATENT DOCUMENTS

EXAMINER INITIALS	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	TRANSLATION YES/NO	
	3-205573	9/1991	Japan				
	4-62857	2/1992	Japan				
	10-281746	10/1998	Japan				
	11-26343	1/1999	Japan				
	2000-164715	6/2000	Japan				
	2000-180143	6/2000	Japan				
	2000-124276	4/2000	Japan				
	2000-174077	6/2000	Japan				
	62-19707	1/1987	Japan				

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)


EXAMINER	DATE CONSIDERED
EXAMINER: Initial citation if reference was considered. Draw line through citation if not in conformance to MPEP 609 and not considered. Include copy of this form with next communication to applicant.	